### **NAME**

CUTEST\_ugrdh - CUTEst tool to evaluate the gradient and Hessian matrix.

### **SYNOPSIS**

```
CALL CUTEST ugrdh( status, n, X, G, lh1, H val )
```

For real rather than double precision arguments, instead

```
CALL CUTEST_ugrdh_s( ... )
```

and for quadruple precision arguments, when available,

```
CALL CUTEST_ugrdh_q( ... )
```

### DESCRIPTION

The CUTEST\_ugrdh subroutine evaluates the gradient and Hessian matrix of the objective function of the problem decoded from a SIF file by the script *sifdecoder* at the point X. This Hessian matrix is stored as a dense matrix.

The problem under consideration is to minimize or maximize an objective function f(x) over all  $x \in \mathbb{R}^n$  subject to the simple bounds  $x^l \le x \le x^u$ . The objective function is group-partially separable.

## **ARGUMENTS**

The arguments of CUTEST\_ugrdh are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error,

n [in] - integer

the number of variables for the problem,

X [in] - real/double precision

an array which gives the current estimate of the solution of the problem,

G [out] - real/double precision

an array which gives the value of the gradient of the objective function evaluated at X,

lh1 [in] - integer

the actual declared size of the leading dimension of H\_val (with lh1 no smaller than N),

H\_val [out] - real/double precision

a two-dimensional array which gives the value of the Hessian matrix of the objective function evaluated at X.

## NOTE

Calling this routine is more efficient than separate calls to CUTEST\_ugr and CUTEST\_udh.

### **AUTHORS**

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# **SEE ALSO**

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads, N.I.M. Gould, D. Orban and Ph.L. Toint, Computational Optimization and Applications **60**:3, pp.545-557, 2014.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited, N.I.M. Gould, D. Orban and Ph.L. Toint, ACM TOMS, **29**:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment, I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint, ACM TOMS, **21**:1, pp.123-160, 1995.

cutest\_cgrdh(3M), sifdecoder(1).